#### 100V<sub>DS</sub>/±20V<sub>GS</sub>/2.5A(I<sub>D</sub>) N-Channel Enha ncement Mode MOSFET

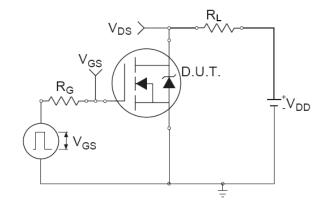
#### **Features**

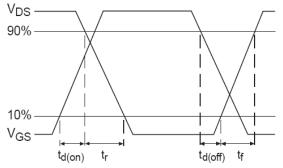
- $V_{DSS}$ =100V/ $V_{GSS}$ =±20V/ $I_{D}$ =2.5A  $R_{DS(ON)}$ =105mΩ(Max.)@ $V_{GS}$ =10V  $R_{DS(ON)}$ =115mΩ(Max.)@ $V_{GS}$ =4.5V
- ESD protect
- Reliable and Rugged
- High Density Cell Design For Ultra Low On-Resistance

### **Applications**

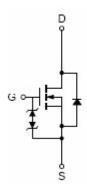
- Synchronous Rectification
- Power Management in Inverter System

# **Switching Time Test Circuit and Waveforms**

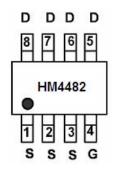




#### **Pin Description**



Marking and pin Assignment





SOP-8 top view

#### Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM4482	HM4482	SOP-8	8#3	) <u>4</u> )	(#)

1

## **Absolute Maximum Ratings** (T<sub>A</sub>=25°C unless otherwise noted)

Symbol	Parameter	Typical	Unit	
$V_{ m DSS}$	Drain-Source Voltage		100	V
$V_{ m GSS}$	Gate –Source Voltage		±20	V
$I_D^{-1}$	Continuous Drain Current	T <sub>C</sub> =70°C	1.8	A
			2.5	A
$I_{DM}^{-1}$	300us Pulsed Drain Current Tested	$T_C=25^{\circ}C$	10	A
$I_S^{-1}$	Diode Continuous Forward Current		3	A
$\mathrm{E_{AS}}^2$	Avalanche Energy, Single Plused(L=0.3mH)		30	mJ
$T_{\mathrm{J}}$	Operating Junction Temperature		150	°C
$T_{STG}$	Storage Temperature Range		-55 ~ 150	°C

Note: 1: Surface Mounted on  $1 \text{in}^2$  pad area,  $t \leq 10 \text{sec.}$ .

#### **Electrical Characteristics** (TA=25°C unless otherwise noted)

Symbol	Parameter	<b>Test Conditions</b>	Min.	Тур	Max.	Unit
Static Char	acteristics					
$\mathrm{BV}_{\mathrm{DSS}}$	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V,I <sub>D</sub> =250uA	100			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}$ =-80V, $V_{GS}$ =0V $T_{J}$ =85°C			1 30	uA
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_D=-250uA$	1.5	2	2.5	V
$I_{GSS}$	Gate Leakage Current	$V_{GS} = \pm 16V, V_{DS} = 0V$			±10	nA
R <sub>DS(on)</sub> <sup>1</sup>	Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =2.5A V <sub>GS</sub> =4.5V, I <sub>D</sub> =2.5A		95 105	105 115	mΩ
Diode Char	acteristics					
${ m V_{SD}}^1$	Diode Forward Voltage	$I_{SD}=3A,V_{GS}=0V$	0.6	0.8	1.1	V
$t_{rr}$	Reverse Recovery Time	$I_{SD}=2.5A,$		44		ns
$Q_{rr}$	Reverse Recovery Charge	$dI_{SD}/dt=100A/us$		80		nC
Dynamic C	haracteristics <sup>2</sup>					
$\begin{array}{c} C_{iss} \\ C_{oss} \\ C_{rss} \end{array}$	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V Frequency=1MHz		940 80 50		pF
$egin{array}{c} t_{ ext{d(on)}} \ t_{ ext{r}} \ t_{ ext{d(off)}} \ t_{ ext{f}} \end{array}$	Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time	$V_{DD}$ =30V, $R_{L}$ =30 $\Omega$ $I_{D}$ =1A, $V_{GEN}$ =10V $R_{G}$ =6 $\Omega$		13 10 32 16	24 19 60 30	ns
	ge Characteristics <sup>2</sup>			10		
$\begin{array}{c} Q_{g} \\ Q_{gs} \\ Q_{gd} \end{array}$	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V <sub>DS</sub> =50V, V <sub>GS</sub> =10V I <sub>D</sub> =2.5A		21 4.9 5.8		nC

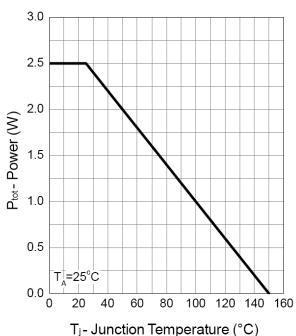
Note: 1: Pulse test; pulse width  $\leq 300$ ns, duty cycle  $\leq 2\%$ .

<sup>2:</sup> UIS tested and pluse width limited by maximum junction temperature 150°C (initial temperature T<sub>J</sub>=25°C).

<sup>2:</sup> Guaranteed by design, not subject to production testing.

# **Typical Characteristics**

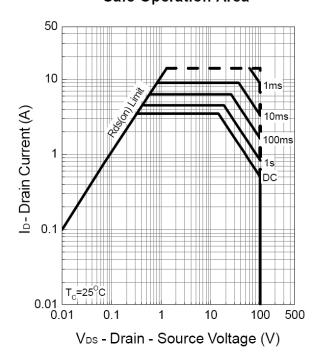
# Power Dissipation



# 4.0 3.5 3.0 (V) 2.5 2.0 1.5 1.0 0.5

**Drain Current** 

#### Safe Operation Area

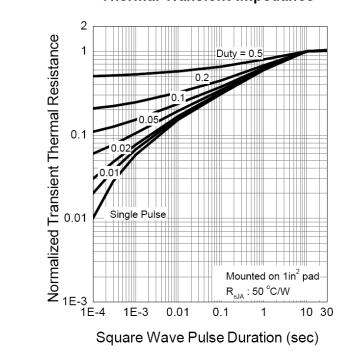


#### Thermal Transient Impedance

80

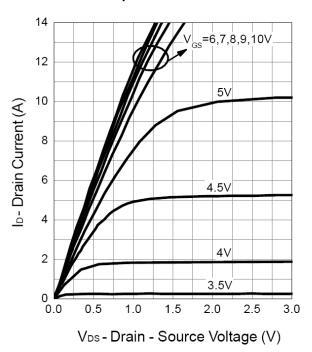
T<sub>j</sub> - Junction Temperature (°C)

100 120

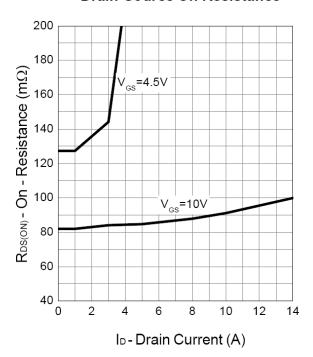


# **Typical Characteristics (Cont.)**

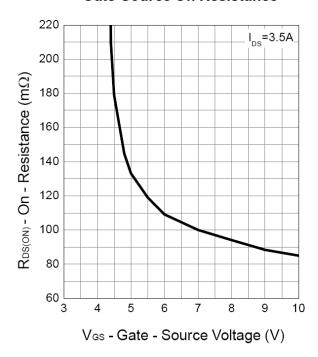
#### **Output Characteristics**



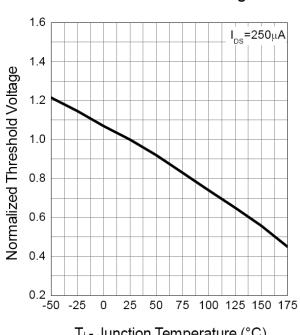
#### **Drain-Source On Resistance**



#### Gate-Source On Resistance

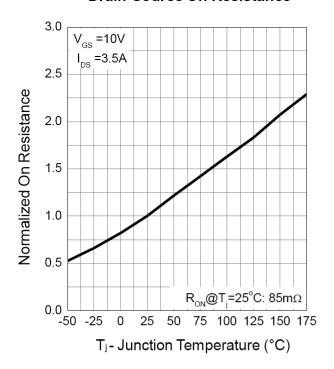


#### Gate Threshold Voltage

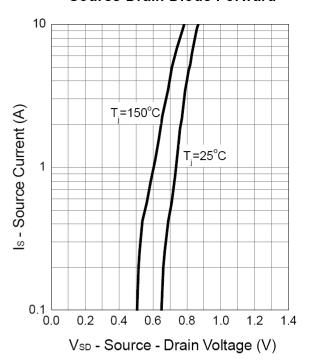


# **Typical Characteristics (Cont.)**

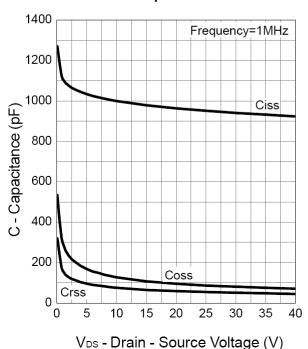
#### **Drain-Source On Resistance**



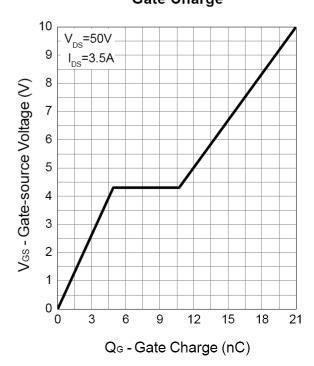
#### Source-Drain Diode Forward

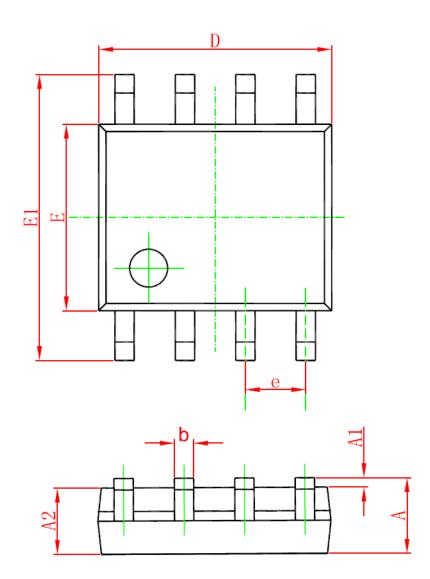


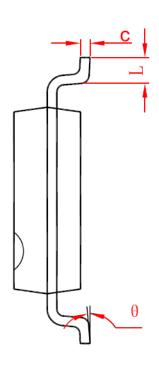
#### Capacitance



**Gate Charge** 







Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min	Max	Min	Max	
Α	1. 350	1. 750	0. 053	0. 069	
A1	0. 100	0. 250	0. 004	0. 010	
A2	1. 350	1. 550	0. 053	0. 061	
b	0. 330	0. 510	0. 013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
Е	3. 800	4. 000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1. 270	0. 016	0. 050	
θ	0°	8°	0°	8°	

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